



30V N-Channel Enhancement Mode Power MOSFET

VDS = 30V, ID = 18A



Description

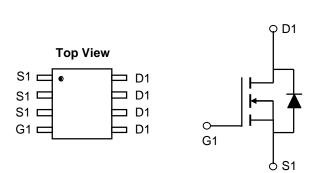
The XPX4410XS uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current

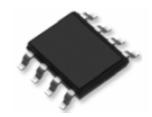
Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



RDS(ON)=4.5mΩ (typ) @ VGS=10V

RDS(ON)=6.0mΩ (typ) @ VGS=4.5V



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX4410XS	XPX4410XS	SOP-8	Ø330mm	12mm	3000

Absolute Maximum Ratings (T_A=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	30	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι _D	18	А
Drain Current-Continuous(T _A =100°C)	I _D (100℃)	13.5	A
Pulsed Drain Current	I _{DM}	78	A
Maximum Power Dissipation	PD	3.5	W
Single pulse avalanche energy (Note 5)	E _{AS}	220	mJ
Operating Junction and Storage Temperature Range	T _J ,T _{STG}	-55 To 150	°C
Thermal Resistance, Junction-to-Ambient ^(Note 2)	R _{0JA}	42	°C/W



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Electrical Characteristics (T_A=25[°]Cunless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	30	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V_{GS} =±20V, V_{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	1.1	1.6	2.0	V
Drain Source On State Desistance		V _{GS} =10V, I _D =10A	-	4.5	6.2	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =10A	-	6.0	7.0	
Forward Transconductance	g fs	V _{DS} =5V,I _D =12A	5	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	Clss	V _{DS} =15V,V _{GS} =0V, F=1.0MHz	-	3819	-	PF
Output Capacitance	Coss		-	350	-	PF
Reverse Transfer Capacitance	C _{rss}		-	240	-	PF
Switching Characteristics (Note 4)	····					
Turn-on Delay Time	t _{d(on)}	V _{DD} =10V,I _D =10A	-	20	-	nS
Turn-on Rise Time	tr		-	15	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10V,R _{GEN} =2.7 Ω	-	60	-	nS
Turn-Off Fall Time	t _f		-	10	-	nS
Total Gate Charge	Qg	V _{DS} =15V,I _D =10A,	-	47.6	-	nC
Gate-Source Charge	Q _{gs}		-	4.9	-	nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V	-	10.9	-	nC
Drain-Source Diode Characteristics	· · ·		-			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-	-	2.0	V
Diode Forward Current (Note 2)	I _S		-	-	18	А

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

2. Surface Mounted on FR4 Board, $t \le 10$ sec.

3. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.

4. Guaranteed by design, not subject to production

5. E_{AS} condition: Tj=25 °C, V_{DD} =15V, V_{G} =10V,L=0.5mH, Rg=25 Ω



V_{GS}=4.5V

I_D=10A

125

150

175

100

30

25° С

0.8

1.0

1.2

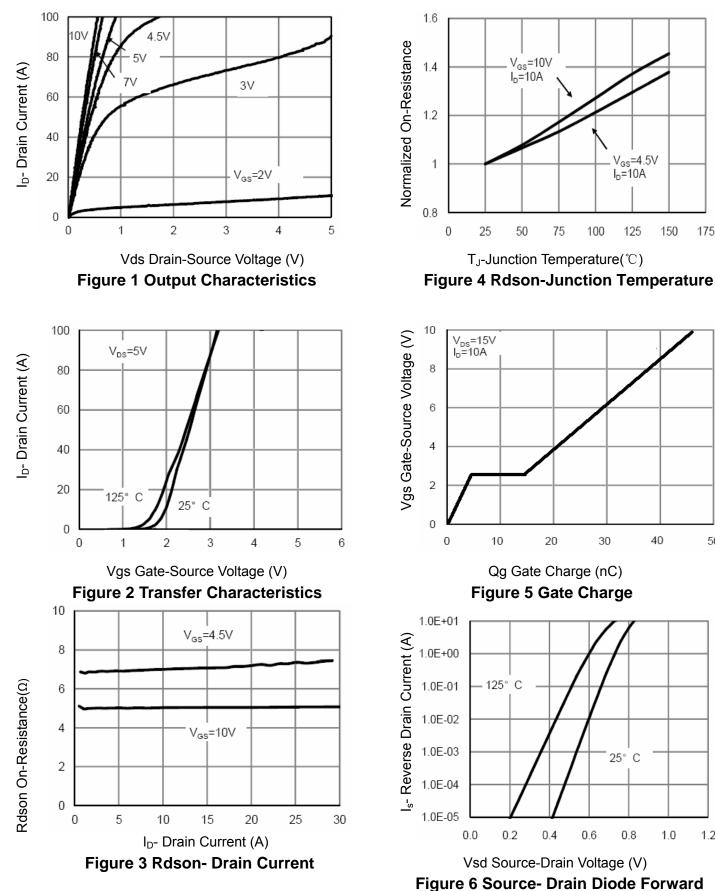
0.6

40

50

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Typical Electrical and Thermal Characteristics (Curves)



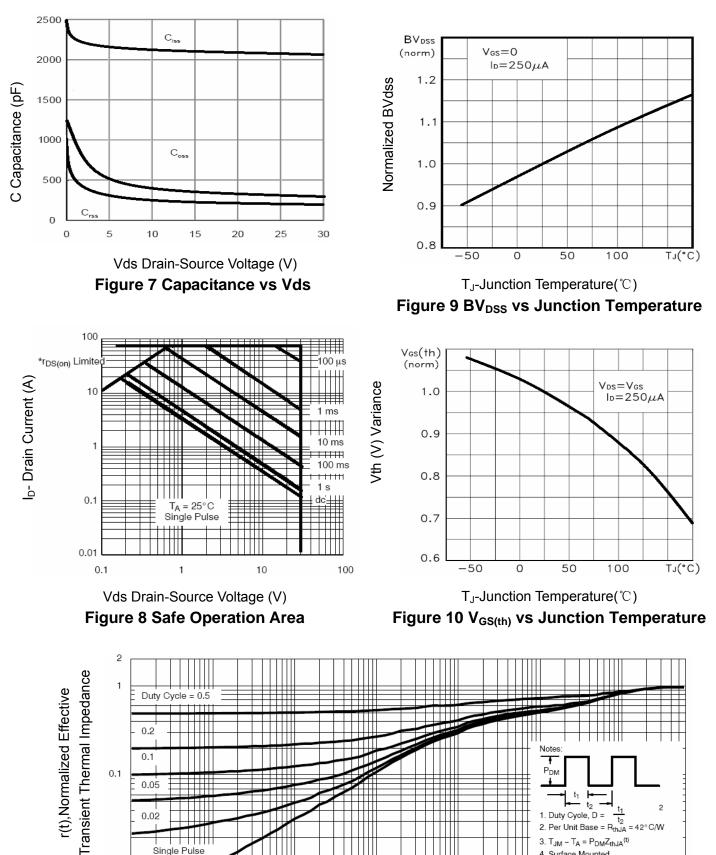


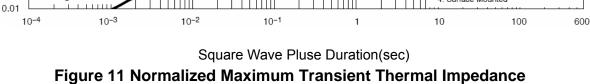
= 42° C/W

3. $T_{JM} - T_A = P_{DM}Z_{thJA}^{(t)}$

4. Surface Mounted

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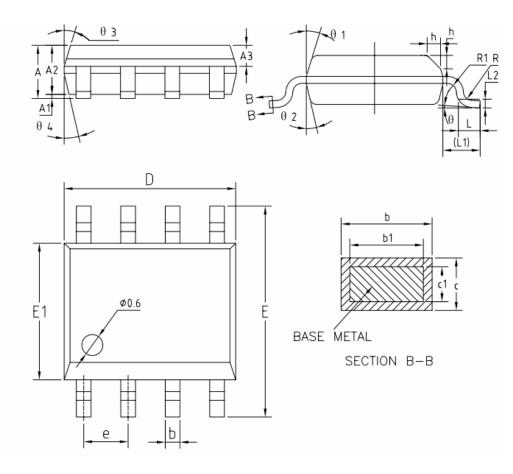


Single Pulse



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SOP-8 Package Information



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

(UNITS OF MEASURE-MILLIMETER)					
SYMBOL	MIN	NOM	MAX		
A	1.35	1.55	1.75		
A1	0.10	0.15	0.25		
A2	1.25	1.40	1.65		
A3	0.50	0.60	0.70		
b	0.38	-	0.51		
b1	0.37	0.42	0.47		
с	0.18	-	0.25		
c1	0.17	0.20	0.23		
D E	4.80	4.90	5.00		
E	5.80	6.00	6.20		
E1	3.80	3.90	4.00		
е	1.17	1.27	1.37		
L L1	0.45	0.60	0.80		
L1	1.04REF				
L2	0.25BSC				
R	0.07	-	-		
R1	0.07	-	-		
h	0.30	0.40	0.50		
θ	0.	-	8'		
θ1	15 '	17 °	19'		
θ2	11'	13'	15 °		
θ <u>3</u>	15 '	17'	19'		
θ4	11'	13°	15*		



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Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃±5 ℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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